

# Anatoli Kniazkov

## List of Publications by Year in descending order

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#	ARTICLE	IF	CITATIONS
1	Reflective Method for Determining the Orientation of the Optical Axis of Uniaxial Crystals and Stressed Materials. , 2018, , .		0
2	The Study of the Surface Distribution of the Electrooptical Properties of the Medium by Reflected Light. Optical Memory and Neural Networks (Information Optics), 2018, 27, 191-195.	1.0	1
3	Measurement of the stress state of materials by reflection of polarization-modulated light. Optics and Spectroscopy (English Translation of Optika I Spektroskopiya), 2017, 122, 338-340.	0.6	1
4	Reflective polarization-modulation method of stress estimation using stress-induced birefringence. Journal of Applied Physics, 2017, 122, 125106.	2.5	4
5	An electric field sensor based on reflected light intensity modulation from electro-optical media. Optical Memory and Neural Networks (Information Optics), 2017, 26, 145-149.	1.0	2
6	Electro-optic study of PZT ferroelectric ceramics using modulation of reflected light. Technical Physics, 2016, 61, 631-634.	0.7	2
7	Estimation of electrooptic coefficients of LiNbO3 and Sr x Ba(1 - x)Nb2O6 crystals by modulation of light reflection coefficient. Optics and Spectroscopy (English Translation of Optika I Spektroskopiya), 2015, 118, 255-258.	0.6	3
8	Reflective method of electro-optic coefficients estimation. Applied Physics B: Lasers and Optics, 2015, 118, 231-234.	2.2	7
9	Speckle-noise computing by two-parameter analysis of the reflected light's periodic variations. Optical Memory and Neural Networks (Information Optics), 2014, 23, 240-245.	1.0	0
10	<title>Portable holographic interferometer for residual stress measurement and nondestructive testing (NDT) of pipelines</title>. , 1999, 3588, 16.		2
11	Advanced holographic nondestructive testing system for residual stress analysis. , 1999, , .		2
12	<title>Stress measurement of deposited SiO2 films on a silicon wafer using dimensional-stability holographic interferometry test</title>. , 1997, 3134, 475.		1
13	<title>Fast residual stress determination of welded joints using reversible holographic interferometric (RHI) film</title>. , 1996, 2861, 32.		1
14	<title>In-situ thin film stress measurement using high-stability portable holographic interferometer</title>. , 1996, , .		1